

<b>Notice of References Cited</b>	Application/Control No. 10/571,288	Applicant(s)/Patent Under Reexamination HEEB ET AL.	
	Examiner Nicholas P. D'Aniello	Art Unit 1793	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Toh et al. "An investigation of the native oxide of aluminum alloy 7475-T7651 using XPS, AES, TEM, EELS, GDOES and RBS", Surface Review and Letters, Volume 10, Issue 02-03 pp. 365-371, published 6/2003
	V	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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